

Notice of Allowability	Application No.	Applicant(s)
	10/536,996 Examiner	YAMAOKA ET AL. Art Unit
	John Teresinski	2858

-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address--

All claims being allowable, PROSECUTION ON THE MERITS IS (OR REMAINS) CLOSED in this application. If not included herewith (or previously mailed), a Notice of Allowance (PTOL-85) or other appropriate communication will be mailed in due course. **THIS NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIGHTS.** This application is subject to withdrawal from issue at the initiative of the Office or upon petition by the applicant. See 37 CFR 1.313 and MPEP 1308.

1. This communication is responsive to 31 May 2005.
 2. The allowed claim(s) is/are 1-9.
 3. Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
 - a) All b) Some* c) None of the:
 1. Certified copies of the priority documents have been received.
 2. Certified copies of the priority documents have been received in Application No. _____.
 3. Copies of the certified copies of the priority documents have been received in this national stage application from the International Bureau (PCT Rule 17.2(a)).
- * Certified copies not received: _____.
- Applicant has THREE MONTHS FROM THE "MAILING DATE" of this communication to file a reply complying with the requirements noted below. Failure to timely comply will result in ABANDONMENT of this application.
THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.
4. A SUBSTITUTE OATH OR DECLARATION must be submitted. Note the attached EXAMINER'S AMENDMENT or NOTICE OF INFORMAL PATENT APPLICATION (PTO-152) which gives reason(s) why the oath or declaration is deficient.
 5. CORRECTED DRAWINGS (as "replacement sheets") must be submitted.
 - (a) including changes required by the Notice of Draftsperson's Patent Drawing Review (PTO-948) attached
 - 1) hereto or 2) to Paper No./Mail Date _____.
 - (b) including changes required by the attached Examiner's Amendment / Comment or in the Office action of Paper No./Mail Date _____.

Identifying indicia such as the application number (see 37 CFR 1.84(c)) should be written on the drawings in the front (not the back) of each sheet. Replacement sheet(s) should be labeled as such in the header according to 37 CFR 1.121(d).
 6. DEPOSIT OF and/or INFORMATION about the deposit of BIOLOGICAL MATERIAL must be submitted. Note the attached Examiner's comment regarding REQUIREMENT FOR THE DEPOSIT OF BIOLOGICAL MATERIAL.

Attachment(s)

1. Notice of References Cited (PTO-892)
2. Notice of Draftperson's Patent Drawing Review (PTO-948)
3. Information Disclosure Statements (PTO-1449 or PTO/SB/08),
Paper No./Mail Date 5/31/2005
4. Examiner's Comment Regarding Requirement for Deposit
of Biological Material
5. Notice of Informal Patent Application (PTO-152)
6. Interview Summary (PTO-413),
Paper No./Mail Date _____.
7. Examiner's Amendment/Comment
8. Examiner's Statement of Reasons for Allowance
9. Other _____.

DETAILED ACTION

EXAMINER'S AMENDMENT

An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it MUST be submitted no later than the payment of the issue fee.

A. In the Abstract:

- a. Line 4, delete "15a, 15b", and replace with --(15a, 15b)--;
- b. Line 9, delete "15a, 15b", and replace with --(15a, 15b)--;
- c. Line 10, delete "comprises", and replace with --having--;
- d. Line 11, delete "20, 30", and replace with --(20, 30)--;
- e. Line 12, delete "80", and replace with --(80)--;
- f. Line 13, delete "20, 30", and replace with --(20, 30)--;
- g. Line 14, delete "The first and";
- h. Delete lines 15-17;

Authorization for this examiner's amendment was given in a telephone interview with Ken-Ichi Hattori on March 16, 2006.

Allowable Subject Matter

Claims 1-9 are allowed.

The following is an examiner's statement of reasons for allowance:

Regarding claims 1, 9 and 14:

The primary reason for the allowance of claims 1 and 4 is the inclusion of wherein said moving means is adapted to move said first detection means across an anchor-end region of each terminal portion of said first comb-shaped conductive pattern supplied with said AC inspection signal and a tip-end region of each terminal portion of said second comb-shaped conductive pattern controlled at said lower-voltage level, and simultaneously move said second detection means across an anchor-end region of each terminal portion of said second comb-shaped conductive pattern and a tip-end region of each terminal portion of said first comb-shaped conductive pattern, whereby said first and second detection means generates detection signals allowing the presence of a defect in each of said first and second comb-shaped conductive patterns to be determined based thereon. It is these features found in the claim, as they are claimed in the combination that has not been found, taught or suggested by the prior art of record, which makes this claim allowable over the prior art.

Claims 2-3 are allowed due to their dependency on claim 1.

Claims 5-9 are allowed due to their dependency on claim 4.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Conclusion

The prior art made of record and not relied upon is considered pertinent to applicant's disclosure. The following is cited to show the state of the art with respect to circuit pattern inspection instruments and pattern inspection methods in general:

U.S. Patent No. 6,995,566 to Yamaoka et al. discloses a circuit pattern inspection apparatus and pattern inspection method including a plurality of finger pattern segments but fails to qualify as prior art due to common inventorship or under double patenting due to differing claim subject matter.

U.S. Patent No. 6,943,559 to Yamaoka et al. discloses a circuit pattern inspection apparatus and pattern inspection method including a plurality of finger pattern segments but fails to qualify as prior art due to common inventorship or under double patenting due to differing claim subject matter.

U.S. Patent No. 5,266,901 to Woo disclose an apparatus and method for resistive detection and waveform analysis of interconnection networks but fails to disclose particulars of the claimed invention, specifically moving means is adapted to move said first detection means across an anchor-end region of each terminal portion of said first comb-shaped conductive pattern supplied with said AC inspection signal and a tip-end region of each terminal portion of said second comb-shaped conductive pattern controlled at said lower-voltage level, and simultaneously move said second detection means across an anchor-end region of each terminal portion of said second comb-shaped conductive pattern and a tip-end region of each terminal portion of said first comb-shaped conductive pattern.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to John Teresinski whose telephone number is (571) 272-2235. The examiner can normally be reached on M-F 8:30 - 5:00.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Diane Lee can be reached on (571) 272-2399. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

JT

JT
March 16, 2006

Anjan Deb

ANJAN DEB
PRIMARY EXAMINER